Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/757,304	SEKINO, TAKASHI	
Examiner	Art Unit	
Batriate t Assessed	0057	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
324	763	10/12/25	PM	
702	117		L	
	$\mathcal{O}^{\mathcal{O}}$	EAUT.		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
PLUS report reviewed and cHacked.	10/12/05	PRO	
EAUT seashed. See a Hacked.	10/12/05	100	
Broad search of:			
204/500, 527, 537			
763,765 702/57,58,64,65 117,120			
7,4/724,775,738 327/1,100			
Keywords: parajitic capacitano divor / comperato			
trans. line topt pottern DC vollage tout			
Ac test			